

**Search Notes**

Application No.

09/255,856

Examiner

Stephen W. Smoot

Applicant(s)

IWASAKI ET AL.

Art Unit

2813

**SEARCHED**

Class	Subclass	Date	Examiner
257	751	5/17/2004	SWS
257	762	5/17/2004	SWS
257	767	5/17/2004	SWS
257	768	5/17/2004	SWS
438	627	5/17/2004	SWS
438	643	5/17/2004	SWS
438	653	5/17/2004	SWS

*S.W.S.***INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Key Words: Interconnects - Copper, Platinum; Plug/Via - Ruthenium;	5/17/2004	<i>S.W.S.</i> SWS
Diffusion Barrier - Titanium Nitride, Ruthenium, Rhodium, Osmium, Iridium, Platinum;	5/17/2004	<i>S.W.S.</i> SWS
Electromigration; Primary Constituents.	5/17/2004	<i>S.W.S.</i> SWS
Search Tools - EAST (attached): USPAT; US PG PUBS; Derwent; EPO; JPO; IBM TDB	5/17/2004	<i>S.W.S.</i> SWS